

Silicon Carbide for advanced in-vivo medical devices

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1st International Conference on Micromachines and Applications

5-30 APRIL 2021 | ONLINE



Bionics –restoring human functionality

- Prosthetics
- Spinal cord repair
- Neural bridge



Playing piano with a mind-controlled robotic arm



Johnny will tell you the movement is slow \rightarrow neural interface would allow more natural movements

Neural Interfaces face many challenges

Long-term in-vivo results in:

- Device failure (50% device failure)
- Tissue damage
- Loss of functionality/performance

- Si arrays (Michigan and Utah) ~ 1-6 months
- Polymer arrays ~ 6-12 months
- Novel coatings ~ 4 years MAX
- A new strategy is clearly needed!
- Cubic SiC \rightarrow excellent neuro and hemacompatibility
- In-vitro and In-vivo (1 month) data \rightarrow solution?

In-vivo challenge – suitable materials for 25+ year operation in the human body



Severe tissue death with W probes

Monolithic 'All-SiC' INI a possible solution



http://www.jhuapl.edu/newscenter/pressreleases/2016/160112.asp



All-SiC neural probe to be packaged with an Omnetics 18 pin nanoconnector to a ZIF connector for animal testing

Osseo-integrated – lets integrate with a robust, long-term neural interface!

In-vitro performance



Biocompatibility

Hemocompatibility

Only 3C-SiC passed all ISO 10993 tests (chem stability, bio- and hemo-compat.)

Saddow et al, IEEE NMDC, Catania, Sicily (IT) October 2014

SiC Intracortical Neural Interfaces (INI)

3C-SiC has properties useful for many biomedical devices, such as neural interfaces:



Implantable Microelectrode Challenges



* [1] J. C. Barrese, J. Aceros, and J. P. Donoghue, "Scanning electron microscopy of chronically implanted intracortical microelectrode arrays in non-human primates," *J Neural Eng.*, vol. 13, p. 026003, Jan 29 2016.

Cubic SiC – Robust Microelectrode?

- SiC is a well-known chemically inert semiconductor:
 - Processed like Silicon (Neuronexus, etc.) \rightarrow Microelectrode array (MEA) capable
 - Grown on Si wafers (low-cost) and micromachining/fab \sim identical to Si
 - Offers larger junction voltages (1.6 V vs. only 0.7V for Si) \rightarrow simulation possible?
- No measured chronic inflammatory response in 2 animal models
- Multitude of solid-state forms:
 - Poly-crystalline and amorphous SiC (*a*-SiC which is an excellent insulator)
 - Single crystal polymorphs (hexagonal and cubic): 3C-SiC with 2.3 eV
 - Allows for microelectrode support, conductor and insulator in single material system



No Immune response in 3 animal models (Mouse, Rat, Pig) to date...

3C-SiC probes vs. coated Si probes



Si and 3C-SiC probes fabricated using same technology 3C-SiC 3X as hard and 3X as flexible:

Measured Mechanical Properties*

Material Type	Hardness [GPa]	Elastic Mod. [GPa]	Fracture tough. [MPa⋅m ^{1/2}]**
(100)Si	12.46 <u>+</u> 0.78	172.13 <u>+</u> 7.76	$\textbf{1.59} \pm \textbf{0.21}$
(100)3C-SiC	31.19 <u>+</u> 3.7	433 <u>+</u> 50	4.6
Poly-3C-SiC	33.54 <u>+</u> 3.3	457 <u>+</u> 50	2.18

* Measured via nanoindentation.

** Crack lengths used to calculate the film fracture toughness.

Main advantage of 3C-SiC instead of polymer-coated Si is thinner probe thickness (6 um vs. 15 um for Si)

*C. Locke, G. Kravchenko, P. Waters, J. Deva Reddy, A. A. Volinsky, C. L. Frewin, S. E. Saddow, ECSCRM '08

Monolithic All-SiC MEA: a robust solution

• In all-SiC technology, a pn diode blocks current flow and an amorphous SiC (*a*-SiC) insulator caps the metallic-like electrodes:



No metals or plastics \rightarrow robust SiC only

How does this work?

- Degenerately doped semiconductors \rightarrow semi-metallic conduction
 - no need for metal electrodes to carry bi-directional signals
- Metal electrodes, such as PtIr, typically processed to form ceramic-like properties
 - 3C-SiC is already a ceramic
- *a*-SiC is highly insulating
 - All-SiC materials integrated to create a monolithic device



All-SiC INI Fabrication flow





Fabrication flow (a through f) for 4H- all-SiC planar neural microelectrode. Fab for 3C-SiC devices identical with underlying Si substrate. Planar MEA Single ended electrodes Double ended resistors PN Diodes

Bernardin, E.K.; Frewin, C.L.; Everly, R.; UI Hassan, J.; Saddow, S.E. Demonstration of a Robust All-Silicon-Carbide Intracortical Neural Interface. *Micromachines* **2018**, *9*, 412. <u>https://doi.org/10.3390/mi9080412</u>

Electrochemical Performance

- Impedance and cyclical voltommetry performed
- Planar all-SiC MEA consistently displayed electrode-like performance
- Dependence on electrode tip area studied
- Capacitive characteristic, as expected, observed



Electrochemical Performance

1.96K μm² = 0.46K μm² =



4H-SiC Electrode CV vs. Area

Increasing recording/stim tip area decreases Z and increases Charge capacity, as expected.

Advantages of Cubic SiC over 4H-SiC

- Biggest challenge is removal of the substrate for implantable MEA's
- One solution is to grow 3C-SiC on SOI ightarrow oxide release layer
- Films grown at IMM-CNR (Catania)
- Allows for integration with electronics (Si) on tab.

Probe release (HF)



Shank \rightarrow 5.1 mm long

Tab \rightarrow 6.64 x 2.3 mm

Newest 16 electrode Monolithic 3C-SiC Implants



Beygi, M., et al, "Fabrication of a Monolithic Implantable Neural Interface from Cubic Silicon Carbide." *Micromachines*, **10** (7), p.430 2019

All-SiC (3C-SiC) Device on SOI

Fabrication of a Monolithic 3C-SiC/SOI Implantable Neural Interface

EIS & CV measurements

- Results of 4 microelectrodes
- Average of 3 replicates
- ► |Z| @ 1kHz → ~165 kΩ
- Electrode-electrolyte shows a predominantly capacitive behavior
- Rate of 50 mV/s



	Anodic	Cathodic
Average Charge Storage Capacity (mC/cm ²)	15.4 ± 1.46	15.2 ± 1.03
Average Charge Per Phase (nC)	75.4 ± 5.06	74.8 ± 5.06

MRI compatible neural interfaces



MRI Images @7T



- Even a thin (~27 um) Si layer results in noticeable image artifacts
- All-SiC free-standing probe displays no artifact @7T and is barely visible!



All-SiC INI (Si device layer)

Free-standing All-SiC INI No Si device layer

Beygi, M.; Dominguez-Viqueira, W.; Feng, C.; Mumcu, G.; Frewin, C.L.; La Via, F.; Saddow, S.E. Silicon Carbide and MRI: Towards Developing a MRI Safe Neural Interface. *Micromachines* 2021, **12**, 126. <u>https://doi.org/10.3390/mi12020126</u>

Summary

- Silicon Carbide is highly neuro-compatible
 - In-vitro and in-vivo (3 animal models) \rightarrow no immune system trigger
- It is possible to create a monolithic INI with only SiC
 - No plastics (polymers) or metals to degrade in-vivo
 - Use of PN junction substrate isolation
 - Use of amorphous SiC capping layer
 - IDE data shows greater than \pm 50V breakdown (I < 1 nA) in 4H-SiC devices
- 3C-SiC on Si and SOI promising to allow for low-cost manufacturing
 - SOI \rightarrow HF dip probe harvest
 - Higher CSC than 4H-SiC but with higher leakage current (Gen 1)
 - Gen 2 fabricated packaging and testing pending
- Preliminary MRI compatibility testing in tissue phantom @7T
 - No visible image artifacts (SiC only)
 - Numerical modeling → below SAR limit (not presented)
 - In-vivo confirmation planned (summer 2021)

Acknowledgments

SiC Bio/Materials Studies

C. Coletti (Tissue) N. Schettini (Blood) C. Frewin (Brain)

Glucose Sensing S. Afroz, F. Cespedes, G. Mumcu

Biosensors

S. Iannota, IMEM-CNR R. Bange, E. Bano, V. Stambouli (DNA)

Simulations

M. Beygi

Deep-Tissue Cancer (NIH R21)

P. Choyke, NCI (Bethesda)A. Gali, Wigner (Budapest)G. Salviati, IMEM-CNR (Parma)

Implantable Neural Interfaces

E. Bernardin (all-SiC)C. Frewin, NeuroNexusJ. Hassan, LIU (Sweden), 4H-SiC epiM. Beygi, MRI compatible interfacesChenyin Feng (C electrodes on SiC)

Fabrication and Processing
R. Everly, NREC
F. La Via, IMM-CNR, 3C-SiC epi
K. Zekentes, E. Bano, V. Stambouli,
IMEP & FORTH, nanopillars

Financial support: DARPA, USF UNI (Crete), NIH R21 (Cancer), USF PEG (Neural Interfaces)





USF Silicon Carbide Biotechnology Group



Spring 2020





















Thank you for your kind attention!



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Prof. Dr. Saddow Overview

- PhD in Electrical Engineering (electrophysics) 1993 (Uni of Maryland)
- Professor of Electrical and Medical Engineering, Uni of South Florida, Tampa, FL
- Develop silicon carbide (SiC) materials and devices for biomedical applications
 - Neural interfaces: Bionics, BMI, etc.
 - In-vivo sensors: blood, etc.
 - Bioelectronics: wearable sensors (wireless sleep, personal locator beacon, etc.)
 - Nanotechnology to treat deep-tissue cancer
- Innovation comes when you work at the nexus of different technologies/fields of endeavor
- In my case EE, physics, chemistry, medicine, material science, mechanics...

Simulation of INI Materials – Brain Phantom

Induced heating caused by interaction with MRI fields \rightarrow tissue damage



Simulated SAR* vs. implant probe material

Material	SAR (W/kg)					
	Whole Head	Inside the box				
		Max 10 g	Max 1 g	Max 0.1 g		
Ref.	2.55	5.83	6.68	7.28		
All-3C-SiC	2.54	5.91	7.16	21.15		
3C-SiC Tip	2.55	5.87	6.75	7.32		
iridium	2.55	6.01	10.82	39.24		
titanium	2.54	5.98	9.51	32.73		
platinum	2.54	5.97	10.36	37.05		
IrO ₂	2.55	6.00	9.39	32.19		
TiN	2.55	5.98	8.87	30.04		

*SAR Specific Absorption Rate (W/kg)

Simulation of INI Materials – Brain Phantom

Image Artifacts caused by interaction with MRI fields \rightarrow difficult to 'see' detail near INI



- Assumed B0=7 T
- FOV=256×256 pixels
- Voxel size 1mm×1mm×1mm
- Max $\Delta B_0 = 100 \mu T \& Min \Delta B_0 = -0.3 \mu T$
- Averaged χ from literature
 - 1) 3C-SiC
 - 2) Si
 - 3) Pt

